

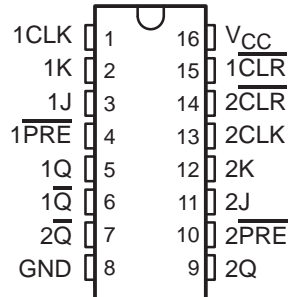
# SN74LVC112A

## DUAL NEGATIVE-EDGE-TRIGGERED J-K FLIP-FLOP WITH CLEAR AND PRESET

SCAS289G – JANUARY 1993 – REVISED SEPTEMBER 1998

- **EPIC™** (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Typical  $V_{OLP}$  (Output Ground Bounce) < 0.8 V at  $V_{CC} = 3.3$  V,  $T_A = 25^\circ\text{C}$
- Typical  $V_{OHV}$  (Output  $V_{OH}$  Undershoot) > 2 V at  $V_{CC} = 3.3$  V,  $T_A = 25^\circ\text{C}$
- Inputs Accept Voltages to 5.5 V
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages

**D, DB, DGV, OR PW PACKAGE  
(TOP VIEW)**



### description

This dual negative-edge-triggered J-K flip-flop is designed for 1.65-V to 3.6-V  $V_{CC}$  operation.

A low level at the preset ( $\overline{\text{PRE}}$ ) or clear ( $\overline{\text{CLR}}$ ) inputs sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{\text{PRE}}$  and  $\overline{\text{CLR}}$  are inactive (high), data at the J and K inputs meeting the setup time requirements is transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the J and K inputs can be changed without affecting the levels at the outputs. The SN74LVC112A can perform as a toggle flip-flop by tying J and K high.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

The SN74LVC112A is characterized for operation from  $-40^\circ\text{C}$  to  $85^\circ\text{C}$ .

**FUNCTION TABLE**

INPUTS					OUTPUTS	
$\overline{\text{PRE}}$	$\overline{\text{CLR}}$	CLK	J	K	Q	$\overline{\text{Q}}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H†	H†
H	H	↓	L	L	$Q_0$	$\overline{Q_0}$
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	Toggle	
H	H	H	X	X	$Q_0$	$\overline{Q_0}$

† The output levels in this configuration may not meet the minimum levels for  $V_{OH}$ . Furthermore, this configuration is unstable; that is, it does not persist when either  $\overline{\text{PRE}}$  or  $\overline{\text{CLR}}$  returns to its inactive (high) level.



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**TEXAS  
INSTRUMENTS**

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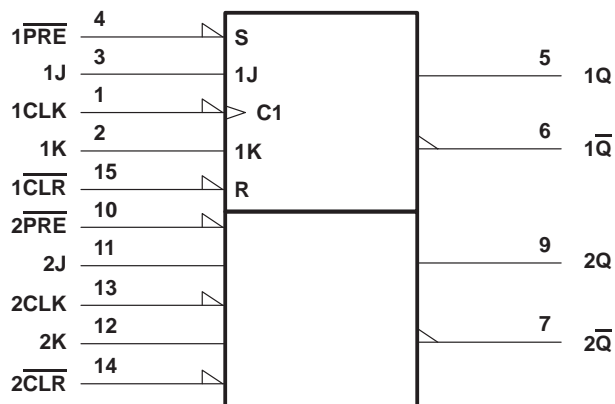
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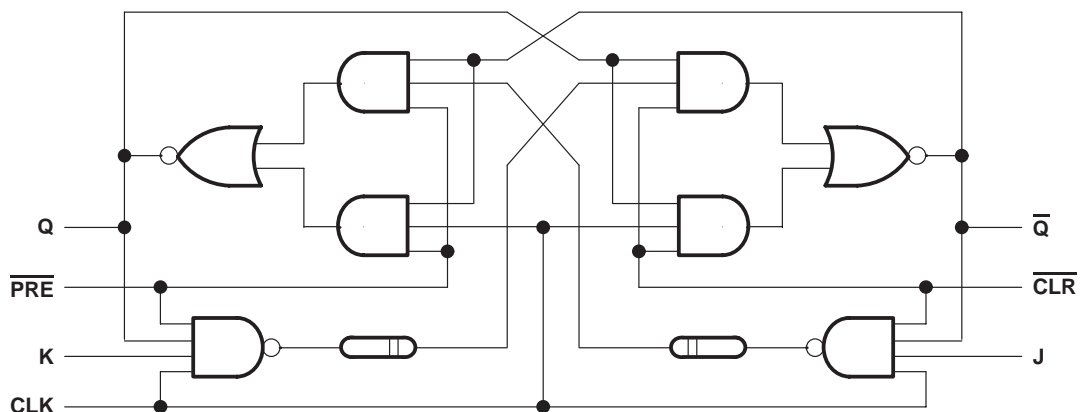
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### logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram, each flip-flop (positive logic)



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$	–0.5 V to 6.5 V
Input voltage range, $V_I$ (see Note 1)	–0.5 V to 6.5 V
Output voltage range, $V_O$ (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, $I_{IK}$ ( $V_I < 0$ )	–50 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ )	–50 mA
Continuous output current, $I_O$	±50 mA
Continuous current through $V_{CC}$ or GND	±100 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): D package	113°C/W
DB package	131°C/W
DGV package	180°C/W
PW package	149°C/W
Storage temperature range, $T_{stg}$	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
  2. The value of  $V_{CC}$  is provided in the recommended operating conditions table.
  3. The package thermal impedance is calculated in accordance with JESD 51.

### recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
$V_{CC}$ Supply voltage	Operating	1.65	3.6	V
	Data retention only	1.5		
$V_{IH}$ High-level input voltage	$V_{CC} = 1.65$ V to $1.95$ V	$0.65 \times V_{CC}$		V
	$V_{CC} = 2.3$ V to $2.7$ V	1.7		
	$V_{CC} = 2.7$ V to $3.6$ V	2		
$V_{IL}$ Low-level input voltage	$V_{CC} = 1.65$ V to $1.95$ V		$0.35 \times V_{CC}$	V
	$V_{CC} = 2.3$ V to $2.7$ V		0.7	
	$V_{CC} = 2.7$ V to $3.6$ V		0.8	
$V_I$ Input voltage		0	5.5	V
$V_O$ Output voltage		0	$V_{CC}$	V
$I_{OH}$ High-level output current	$V_{CC} = 1.65$ V		–4	mA
	$V_{CC} = 2.3$ V		–8	
	$V_{CC} = 2.7$ V		–12	
	$V_{CC} = 3$ V		–24	
$I_{OL}$ Low-level output current	$V_{CC} = 1.65$ V		4	mA
	$V_{CC} = 2.3$ V		8	
	$V_{CC} = 2.7$ V		12	
	$V_{CC} = 3$ V		24	
$\Delta t/\Delta v$ Input transition rise or fall rate		0	10	ns/V
$T_A$ Operating free-air temperature		–40	85	°C

NOTE 4: All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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## DUAL NEGATIVE-EDGE-TRIGGERED J-K FLIP-FLOP

### WITH CLEAR AND PRESET

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**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP†	MAX	UNIT
V <sub>OH</sub>	I <sub>OH</sub> = –100 µA	1.65 V to 3.6 V	V <sub>CC</sub> –0.2			V
	I <sub>OH</sub> = –4 mA	1.65 V	1.2			
	I <sub>OH</sub> = –8 mA	2.3 V	1.7			
	I <sub>OH</sub> = –12 mA	2.7 V	2.2			
		3 V	2.4			
	I <sub>OH</sub> = –24 mA	3 V	2.2			
V <sub>OL</sub>	I <sub>OL</sub> = 100 µA	1.65 V to 3.6 V			0.2	V
	I <sub>OL</sub> = 4 mA	1.65 V			0.45	
	I <sub>OL</sub> = 8 mA	2.3 V			0.7	
	I <sub>OL</sub> = 12 mA	2.7 V			0.4	
	I <sub>OL</sub> = 24 mA	3 V			0.55	
I <sub>I</sub>	V <sub>I</sub> = 5.5 V or GND	3.6 V			±5	µA
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	3.6 V			10	µA
ΔI <sub>CC</sub>	One input at V <sub>CC</sub> – 0.6 V, Other inputs at V <sub>CC</sub> or GND	2.7 V to 3.6 V			500	µA
C <sub>i</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	3.3 V		4.5		pF

† All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

**timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)**

			V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>clock</sub>	Clock frequency		‡		‡		150		150		MHz
t <sub>w</sub>	Pulse duration, CLK high or low		‡		‡		3.3		3.3		ns
t <sub>su</sub>	Setup time	Data before CLK↓	‡		‡		2.3		3.1		ns
		PRE or CLR inactive	‡		‡		1.1		2.4		
t <sub>h</sub>	Hold time, data after CLK↓		‡		‡		0.7		2.5		ns

‡ This information was not available at the time of publication.

**switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)**

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V			UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	TYP	MAX	
f <sub>max</sub>			‡		‡		150		150			MHz
t <sub>pd</sub>	CLR or PRE	Q or $\bar{Q}$	‡	‡	‡	‡	5.5		1	3.4	4.8	ns
	CLK		‡	‡	‡	‡	7.1		1	3.5	5.9	

‡ This information was not available at the time of publication.



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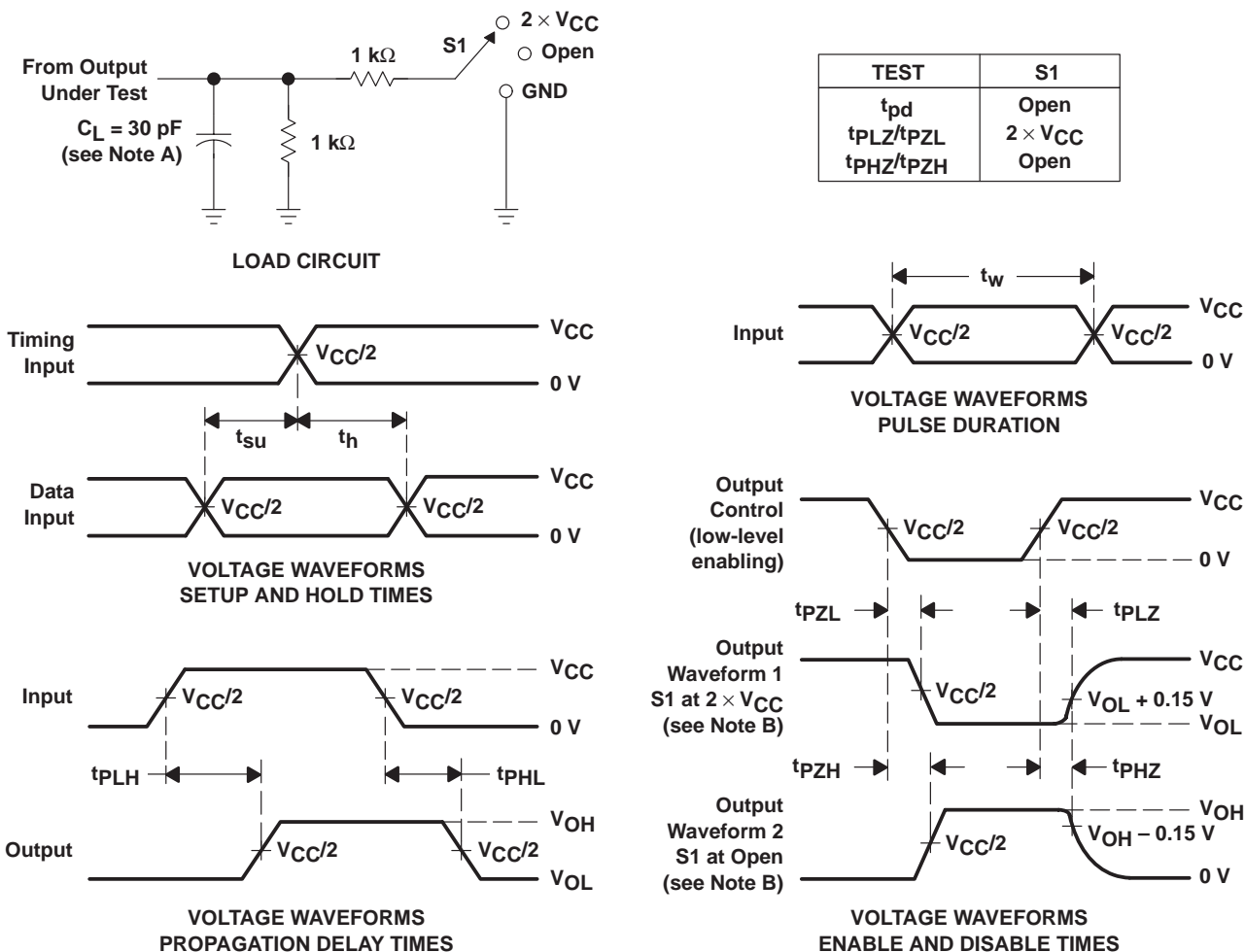
operating characteristics,  $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	$V_{CC} = 1.8\text{ V}$ $\pm 0.15\text{ V}$	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}$	$V_{CC} = 3.3\text{ V}$ $\pm 0.3\text{ V}$	UNIT
		TYP	TYP	TYP	
$C_{pd}$ Power dissipation capacitance per flip-flop	$f = 10\text{ MHz}$	†	†	24	pF

† This information was not available at the time of publication.

### PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 1.8\text{ V} \pm 0.15\text{ V}$



- NOTES:
- A.  $C_L$  includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10\text{ MHz}$ ,  $Z_O = 50\ \Omega$ ,  $t_r \leq 2\text{ ns}$ ,  $t_f \leq 2\text{ ns}$ .
  - D. The outputs are measured one at a time with one transition per measurement.
  - E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
  - F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
  - G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 1. Load Circuit and Voltage Waveforms



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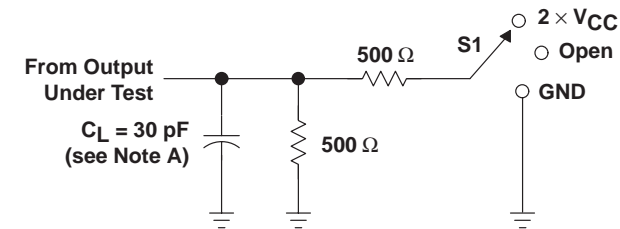
## DUAL NEGATIVE-EDGE-TRIGGERED J-K FLIP-FLOP

### WITH CLEAR AND PRESET

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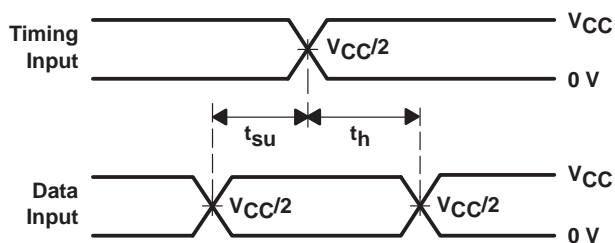
#### PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$$

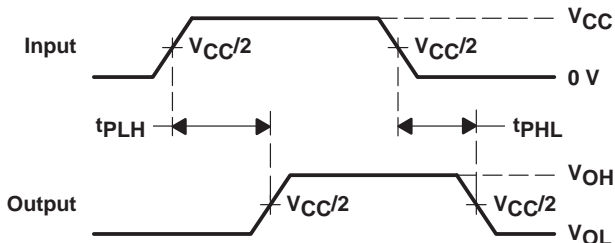


LOAD CIRCUIT

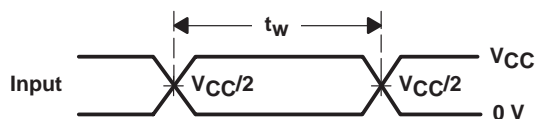
TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	2 $\times V_{CC}$
$t_{PHZ}/t_{PZH}$	GND



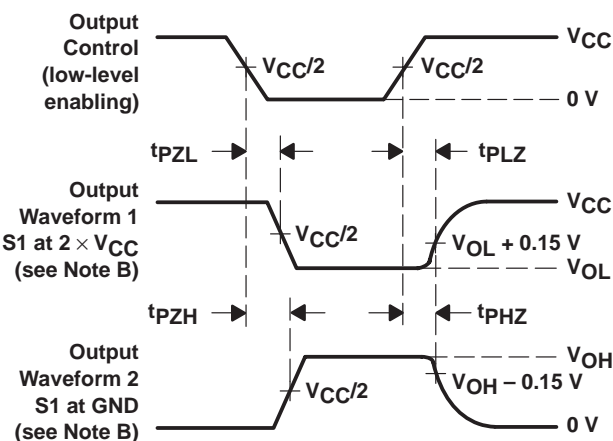
VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES

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  - All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r \leq 2 \text{ ns}$ ,  $t_f \leq 2 \text{ ns}$ .
  - The outputs are measured one at a time with one transition per measurement.
  - $t_{pLZ}$  and  $t_{pHZ}$  are the same as  $t_{dis}$ .
  - $t_{pZL}$  and  $t_{pZH}$  are the same as  $t_{en}$ .
  - $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 2. Load Circuit and Voltage Waveforms

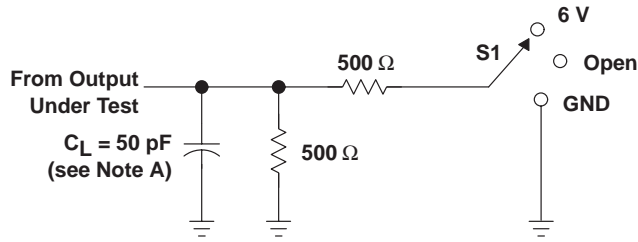
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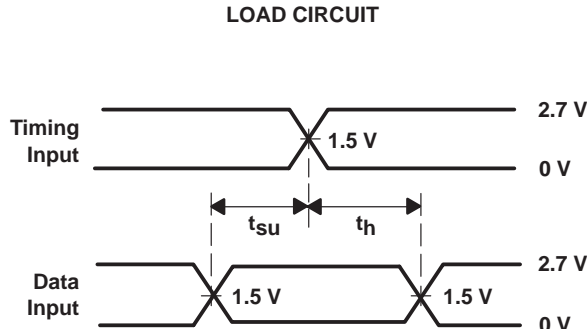
### PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.7\text{ V AND } 3.3\text{ V} \pm 0.3\text{ V}$

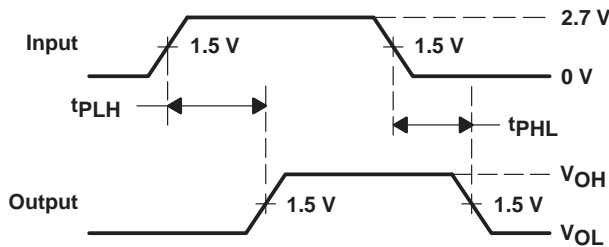


LOAD CIRCUIT

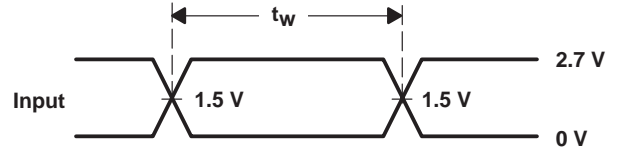
TEST	S1
$t_{pd}$	Open
$t_{PLZ}/t_{PZL}$	6 V
$t_{PHZ}/t_{PZH}$	GND



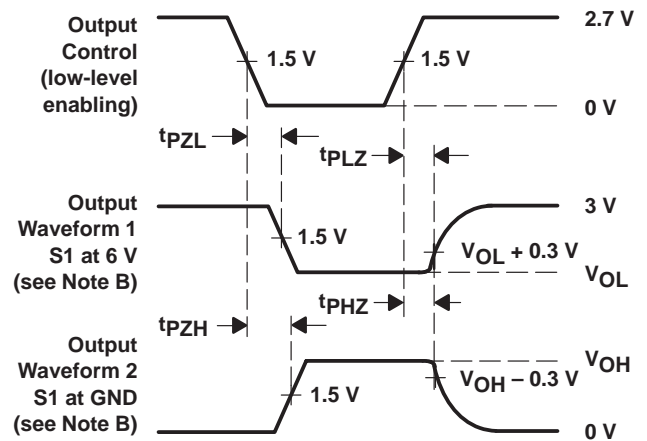
VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
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  - D. The outputs are measured one at a time with one transition per measurement.
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  - G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .

Figure 3. Load Circuit and Voltage Waveforms

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